



Full Length Article



## Fabrication of highly sensitive room temperature operated NO<sub>2</sub> gas sensor using back gated 2D-MoS<sub>2</sub> FETs

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### ABSTRACT

Atomically thin layered semiconductors such as Molybdenum Sulphide (MoS<sub>2</sub>) have emerged as potential candidate for trace level detection of chemicals owing to their innate very high surface to volume ratio. Present work focuses on the fabrication of room temperature operated Nitrogen dioxide (NO<sub>2</sub>) gas sensor exploiting MoS<sub>2</sub> as gas sensing matrix. Three different sensor structures, (i) Au/Cr/single layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si, (ii) Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si, and (iii) Au/Cr/ten-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si were fabricated and gas sensing measurements were carried out for different NO<sub>2</sub> gas concentrations (1 ppm to 500 ppm). Effect of NO<sub>2</sub> gas adsorption on MoS<sub>2</sub> surface was explained using realignment of energy band diagram. Sensing response (%) for Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si structure was found to be maximum as compared to the case of single layer and ten-layer structure and corresponding sensing mechanism has been investigated in detail. Response and recovery time of fabricated Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si sensor were found to be 24 s and 41 s respectively, and cross selectivity measurements were performed and sensor was found to be highly selective towards NO<sub>2</sub> gas. Present work pave the way to realize the potential of MoS<sub>2</sub> based back gated Field Effect Transistors (FETs) for fabricating highly efficient NO<sub>2</sub> gas sensors.

### 1. Introduction

Gas sensing technology plays an important role in human and environmental security. The detection of toxic gases within a limited time frame is critical since its minor leakage can be extremely harmful to the living beings. There are several categories of materials which are conventionally used for the detection of these harmful/toxic gases such as metal oxides (thin and thick films) [1–4], nanorods [5–7], nanowires [8–10], conducting polymers [11–13] etc. Apart from that, in recent times, self-powered and wearable gas sensors are also becoming widely popular [14–18]. Metal-oxide based gas sensors have outperformed the other conventional materials due to their relative ease of fabrication making it a low-cost solution, good performance, ease of modification

for enhancement of sensing performance, stability and industrial compatibility [19]. However, there are few issues with these metal-oxide based gas sensors: (i) their operating temperature is high (> 100 °C) which leads to a high power consumption [20], (ii) due to the high operating temperature there are undesired modification of grains in the matrix leading to the drift in performance [21], and (iii) they possess poor selectivity [22–24]. Conducting polymers are promising in this regard because they perform satisfactorily at room temperature (RT) but they are unstable and very sensitive to the humidity so that their device performance degrades in air and thus face problems with practical applications [25–27]. Recently 2D semiconducting materials such as MoS<sub>2</sub> has gathered lot of attention as sensors [28–31]. MoS<sub>2</sub> based FETs are extremely promising as gas sensing platform along with the advantage of

*Abbreviations:* MoS<sub>2</sub>, molybdenum sulphide; NO<sub>2</sub>, nitrogen dioxide; FETs, field effect transistors; RT, room temperature; DFT, density functional theory; LOD, limit of detection; HNPs, Hexagonal nanoplates; CNTs, Carbon nanotubes; PLD, Pulsed Laser Deposition; 2DSCs, Two-dimensional semiconductors; vdW, van der Waal; SR, Sensor Response.

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**Table 1**  
Deposition parameters for growing MoS<sub>2</sub> layers using PLD technique.

Process gas	N <sub>2</sub>
Substrate Temperature	800 °C
Laser Fluence	0.8 J/cm <sup>2</sup>
Growth pressure (Torr)	10 <sup>-3</sup>
Target to Substrate distance	6 cm
Numbers of Laser pulses	50, 150 and 400
Number of layers	1, 4 and 10

**Table 2**  
Process parameter for deposition of metal electrodes on MoS<sub>2</sub> surface.

Electrode	Au/Cr
Deposition Technique	Thermal Evaporation
Source	Au/Cr wire
Filament current (A)	150/120 A
Growth pressure (Torr)	10 <sup>-6</sup>
Target Substrate distance (cm)	12
Deposition Time (min)	5

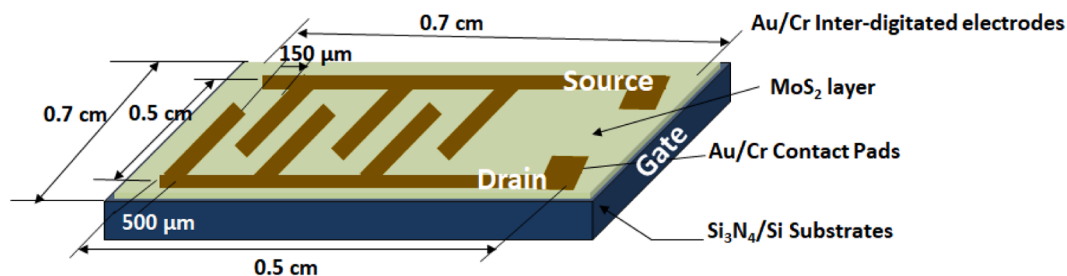
better electrostatic control to modulate the charge transfer process via MoS<sub>2</sub> due to interacting analyte. Density functional theory (DFT) suggests that MoS<sub>2</sub> surface have very good interaction coefficient for various hazardous gases like NO<sub>2</sub>, SO<sub>2</sub>, CO and NO etc. [32]. He et.al. fabricated flexible array of transistor utilizing MoS<sub>2</sub> as semiconducting channel and reduced graphene oxide as source-drain electrodes. They dispersed platinum (Pt) nanoparticles on the surface and achieved Limit of Detection (LOD) of 2 ppb with sensitivity of 6.1 % towards NO<sub>2</sub> gas [33]. Niu et.al. synthesized graphene/MoS<sub>2</sub> composite utilizing wet-spinning and hydrothermal method, and reported the LOD of 50 ppm towards NO<sub>2</sub> (sensitivity of 40 %) and 1000 ppm (sensitivity of 110 %) towards NH<sub>3</sub> gas respectively. rGO/MoS<sub>2</sub> composite based sensor showed sensitivity of 59.8 % towards 2 ppm NO<sub>2</sub> gas and achieved the LOD of 5.7 ppb at operating temperature of 60 °C [34]. Pham et al. demonstrated the role of incident photon with energy matching with band gap energy for enhancing the performance of MoS<sub>2</sub> based gas sensor [35]. They fabricated Au/Gr/MoS<sub>2</sub>/Gr/Au/SiO<sub>2</sub>/Si structure for sensing the NO<sub>2</sub> gas and achieved sensitivity of 3.3/ppb with LOD of 0.1 ppb for MoS<sub>2</sub> channel as sensing matrix. This concept paved the way for enhancing the interaction of 2D materials with analytes using the illumination of photon with energy equals to its band gap [35]. Wu et al. synthesized MoS<sub>2</sub>/Si heterojunction where large area MoS<sub>2</sub> layers were synthesized by two step thermal decomposition process and Si nanowire (NW) array via chemical etching method [36]. Fabricated MoS<sub>2</sub>/Si detected NO gas and reported the LOD to be 50 ppm with excellent repeatability and stability [36]. Park et.al demonstrated the advantage of dispersion of Pt nanoparticle on MoS<sub>2</sub>, and achieved the LOD of 130 ppb and 5 ppm for NH<sub>3</sub> and H<sub>2</sub>S gas respectively [37]. Wang et.al. demonstrated the interaction between MoS<sub>2</sub> and various gases using DFT and reported that CO (calculated adsorption energy is - 0.980 eV) and CH<sub>4</sub> (calculated adsorption energy is -0.710 eV) chemically adsorb on the MoS<sub>2</sub> surface whereas H<sub>2</sub> (calculated adsorption energy is -0.563 eV) follows the physical adsorption [38]. The fabricated Au-microsphere based sensor showed response of 25.48, 16.75, and 8.48 for 30 ppm of

CO (operating temperature = 150 °C), CH<sub>4</sub> (operating temperature = 150 °C) and H<sub>2</sub> (operating temperature = 175 °C) respectively [38]. Deokar et.al. demonstrated unique coexistence of n-type and p-type region in synthesized hexagonal nanoplates (HNPs) over vertically grown carbon nanotubes (CNTs) using CVD technique [39]. They exploited the fabricated MoS<sub>2</sub> (HNPs)/CNT hybrid-based sensor for room temperature detection of NO<sub>2</sub> gas with LOD of 25 ppb. Their DFT calculation showed enhanced charge transfer at the comparably more active edge sites in HNPs MoS<sub>2</sub> [39]. Li et al. fabricated single and multilayer mechanically exfoliated MoS<sub>2</sub> based FET on SiO<sub>2</sub>/Si substrates for sensing the NO gas at room temperature. The LOD of their sensor was 0.8 ppm and found that current stability of multilayer device is better than single layer device upon exposure of NO gas [40]. In summary, MoS<sub>2</sub> based sensors reported in literature are either having poor sensing response or working at relatively higher operating temperature. Apart from that, FET based sensors are scarcely reported. Thus, efforts have been made in the present work to resolve these issues by using pulsed laser deposition (PLD) grown MoS<sub>2</sub> layers.

Hence in the present work, an attempt has been made to fabricate highly sensitive room temperature (~27 °C) operated field effect transistor based NO<sub>2</sub> gas sensor using 2D-MoS<sub>2</sub> as gas sensing matrix. To explore the effect of gate modulation on the MoS<sub>2</sub> FET based sensor, three different configurations of sensor structure i.e. (i) Au/Cr/single layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si, (ii) Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si and (iii) Au/Cr/ten-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si have been investigated in detail.

## 2. Experimental section

A 90 nm thin Si<sub>3</sub>N<sub>4</sub> layer was grown on Si ( $n^{++}$ , resistivity: 0.001–0.005 Ω-cm) substrate using plasma enhanced chemical vapor deposition (PECVD) technique. Three different thicknesses of MoS<sub>2</sub> were deposited, (i) single-layer (50 laser pulses at 800 °C substrate temperature), (ii) four-layer (150 laser pulses at 800 °C substrate temperature), and (iii) ten-layer (400 laser pulses at 800 °C substrate temperature) to see its effect on gas sensing performance. Different number of MoS<sub>2</sub> layers were grown using PLD technique and its optimization along with fabrication of FETs were reported in our previous work [41–43]. Since gas sensing is a surface dominating phenomenon, single-layer which have maximum possible surface to volume ratio and ten-layer MoS<sub>2</sub> (Bulk) having comparatively lesser surface to volume ratio were chosen. The gas sensors were fabricated by patterning the interdigitated electrode of gold (Au)/chrome (Cr) on MoS<sub>2</sub> layers using shadow mask. Process parameters involved in depositing the different MoS<sub>2</sub> layers are listed in Table 1. Au and Cr electrodes were deposited using pure metal (99.999 %) wire by thermal evaporation technique. The optimized process parameters for deposition of Au (50 nm)/Cr (50 nm) are listed in Table 2. Fig. 1 shows the schematic of the fabricated gas sensor using MoS<sub>2</sub> as gas sensing matrix, heavily doped Si as back gate and Au/Cr electrodes as source drain contacts. The three terminal electrical measurements for the fabricated MoS<sub>2</sub> based gas sensors with and without inclusion of gases were recorded using Keithley 4200 semiconductor characterization system which is integrated with probe station (Make: CASCADE Microtech, Germany).



**Fig. 1.** Schematic of fabricated gas sensor for sensing NO<sub>2</sub> gas using MoS<sub>2</sub> layer as sensing matrix.

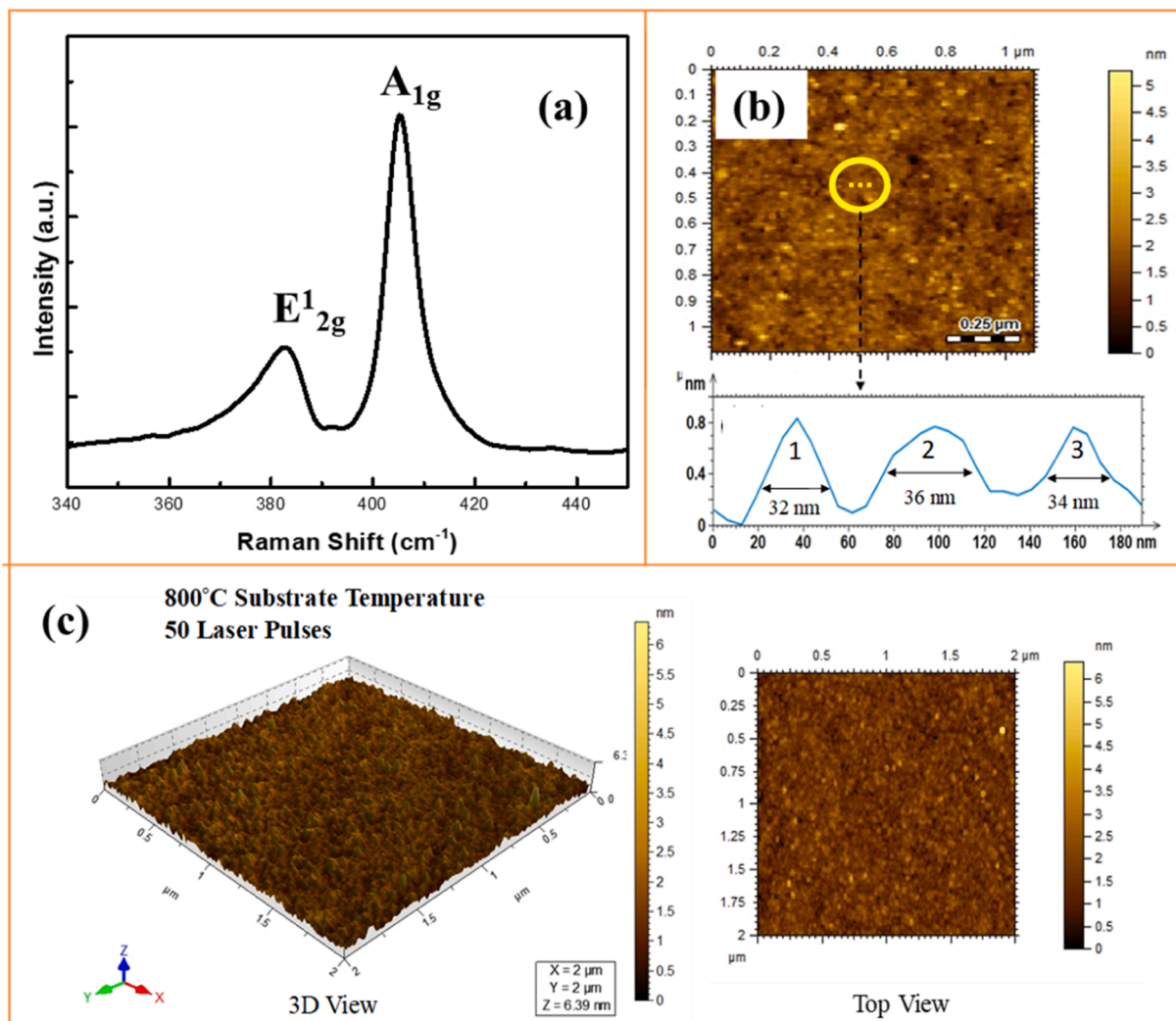


Fig. 2. Structural and surface morphologies studies of MoS<sub>2</sub> single layer: (a) Raman Spectra, AFM Profile (b) for 3 consecutive grains and (c) 3D view and top view of profile.

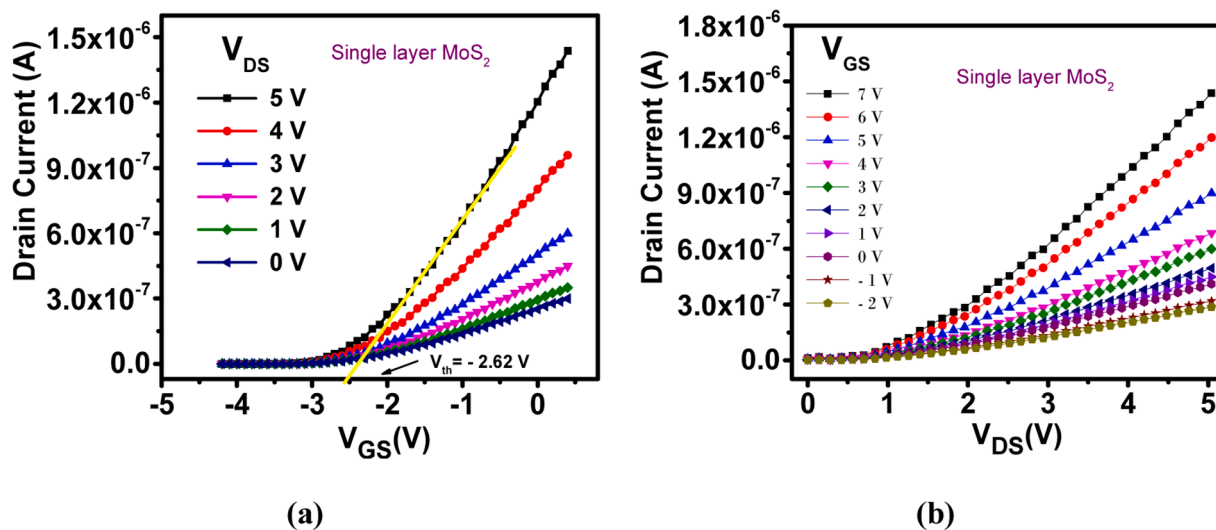


Fig. 3. (a) Transfer curve, and (b) output curve of the fabricated single layer MoS<sub>2</sub> FET.

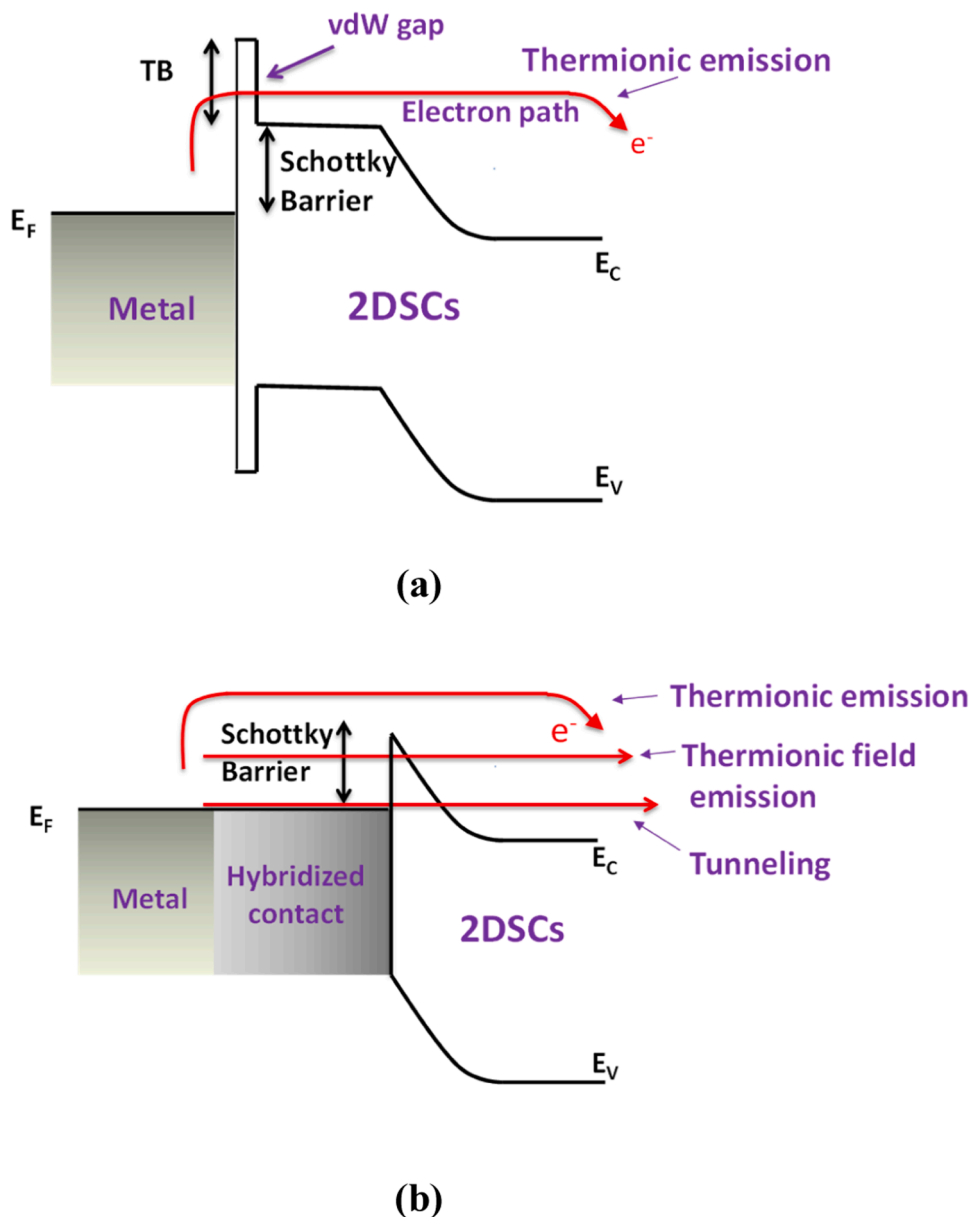


Fig. 4. Schematic of energy band diagram for (a) metal contact/2DSCs interface with van der Waals gap, and (b) metal contact/2DSCs interface with hybridization e.g., Chromium-MoS<sub>2</sub> interface.

### 3. Results and discussion

#### 3.1. Characterization

Raman measurements of MoS<sub>2</sub> thin films grown using 50 laser pulses at substrate temperatures of 800 °C were carried out and the corresponding Raman spectra has been shown in Fig. 2(a). Peaks corresponding to E<sub>2g</sub><sup>1</sup> and A<sub>1g</sub> phonon modes were observed at 385.4 cm<sup>-1</sup> and 405.2 cm<sup>-1</sup> in the Raman spectrum respectively (Fig. 2(a)), confirming the growth of 2H-MoS<sub>2</sub> on passivated Si substrate. The wave-number difference (directly correlated to the number of MoS<sub>2</sub> layers) between the two modes was estimated to be around  $\Delta\omega \approx 19.8$  cm<sup>-1</sup> for the prepared MoS<sub>2</sub> single layer. Fig. 2(b) show the 1 × 1 μm<sup>2</sup> scanned area of the sample grown with 50 laser pulses (monolayer), along with the corresponding grain size distribution profile. Three consecutive grains of the sample were profiled and corresponding distribution shows non-uniform distribution of the three consecutive grains (32 nm, 36 nm and 34 nm) suggesting inhomogeneous growth of MoS<sub>2</sub> monolayer by

PLD at 800 °C using 50 laser pulses. Fig. 2(c) shows the 3D and top view micro-images of the MoS<sub>2</sub> monolayers grown at substrate temperature of 800 °C with 50 laser pulses. Scanning area of the samples was fixed at 2 × 2 μm<sup>2</sup>. The step coverage of the sample grown at 800 °C is continuous (Fig. 2(c)) indicating the growth of high quality MoS<sub>2</sub> layers, which is in accordance with the results obtained using Raman spectroscopy for sample grown with 50 laser pulses.

#### 3.2. Gas sensing using single layer MoS<sub>2</sub> as gas sensing matrix

MoS<sub>2</sub> possess very high surface to volume ratio specially in their single layer form. Gas sensing is surface dominating phenomenon and thus atomically thin layered material is expected to offer high detection capability for the incident chemical species. For the semiconducting materials, their conductance plays an important role in the detection capability which can be effectively tuned using gate terminal of FET. MoS<sub>2</sub> is an atomically thin layered semiconductor which gives extra degree of freedom to modulate its conductance using back-gate. By

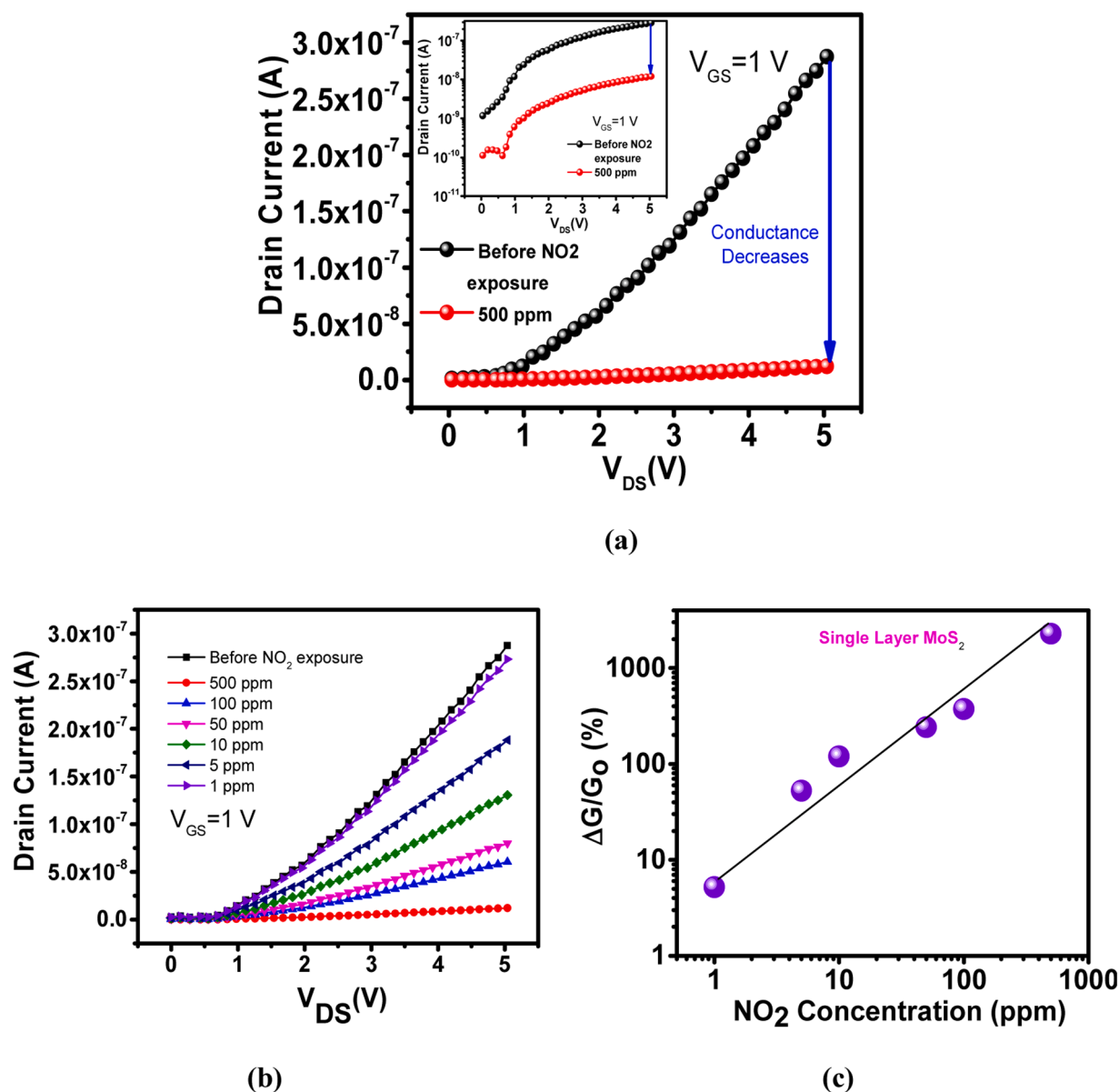


Fig. 5. Output curve for single layer MoS<sub>2</sub> FET sensor at  $V_{GS} = 1$  V without and with exposure towards (a) 500 ppm NO<sub>2</sub> gas, and (b) towards different concentration (1 ppm to 500 ppm) of NO<sub>2</sub>, and (c) sensor response variation with concentration of NO<sub>2</sub> gas on logarithmic scale.

effective modulation from back-gate, one can manipulate the properties of the active matrix to enhance its sensing functionalities [44]. It may be noticed that, “back-gate” geometry of FETs is extremely useful for gas sensing applications as it can provide both, (i) effective interaction area of sensing matrix for target gas species, and (ii) necessary modulation of channel conductance from back-gate. Fig. 3(a) and (b) show the transfer and output characteristic curves for the fabricated back-gated FET using MoS<sub>2</sub> as semiconducting channel respectively. It can be observed from Fig. 3(a) that fabricated transistor shows n-type behavior of semiconducting MoS<sub>2</sub> with a threshold voltage of  $-2.62$  V. The mobility of the fabricated device using single layer MoS<sub>2</sub> was estimated to be  $21.5 \text{ cm}^2\text{V}^{-1}\text{S}^{-1}$  with  $I_{on/off}$  ratio  $3.4 \times 10^4$ . The shape observed in output curve (Fig. 3(b)) for MoS<sub>2</sub> devices originates from the existence of Schottky barrier at MoS<sub>2</sub> and Cr interface and these kind of devices are proven to be more advantageous for sensing study related to gas-solid interactions [45]. Since monolayer MoS<sub>2</sub> possess high surface area and top side of its surface is open to ambient, charge transport is expected to be very sensitive to the interaction with target gas molecules.

In contrast with the metal contact with three-dimensional

semiconductors, pristine surface of two-dimensional semiconductors (2DSCs) avoid forming covalent bonds with many metals in top-contact configuration [45]. If there is no hybridization between 2DSCs and metal contact, there exist additional van der Waal (vdW) gap (tunnel barrier) between the two. This existence of vdW greatly reduces the carrier injection compared to the case when there is no vdW gap (only inherent Schottky barrier is there [45]). The former case is seen in MoS<sub>2</sub> with metal contacts like Gold (Au) while the presence of metal like Cr forbids the formation of vdW gap and only an inherent Schottky barrier is formed [45]. Cr with MoS<sub>2</sub> gives rise to the formation of a hybrid contact due to formation of bonds between metal and 2DSCs [45–47]. Fig. 4(a) and (b) show the schematic of energy band diagram to understand this better. A tunnel barrier (TB) is formed due to vdW gap between gold with 2DSCs as shown in Fig. 4(a) restricting the flow of charge carriers. In this case electron flow from metal to semiconductor is possible only through thermionic emission [45]. On the other hand, use of metals like Cr with 2DSCs materials is reported to form a hybridized contact with 2DSCs avoiding the formation of TB (Fig. 4(b)). The presence of this hybridized contact facilitates the flow of charge carriers

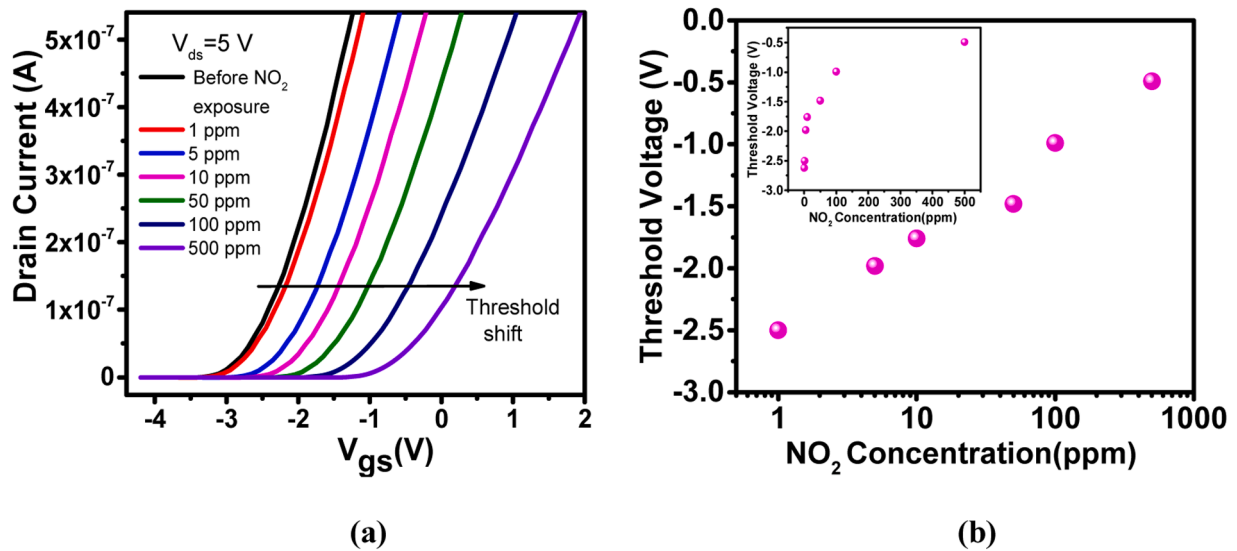


Fig. 6. (a) Transfer curve at  $V_{DS} = 5$  V of single layer  $\text{MoS}_2$  FET sensor towards  $\text{NO}_2$  gas from 1 ppm to 500 ppm, and (b) threshold voltage variation with gas concentration on logarithmic scale and inset shows the same variation on linear scale.

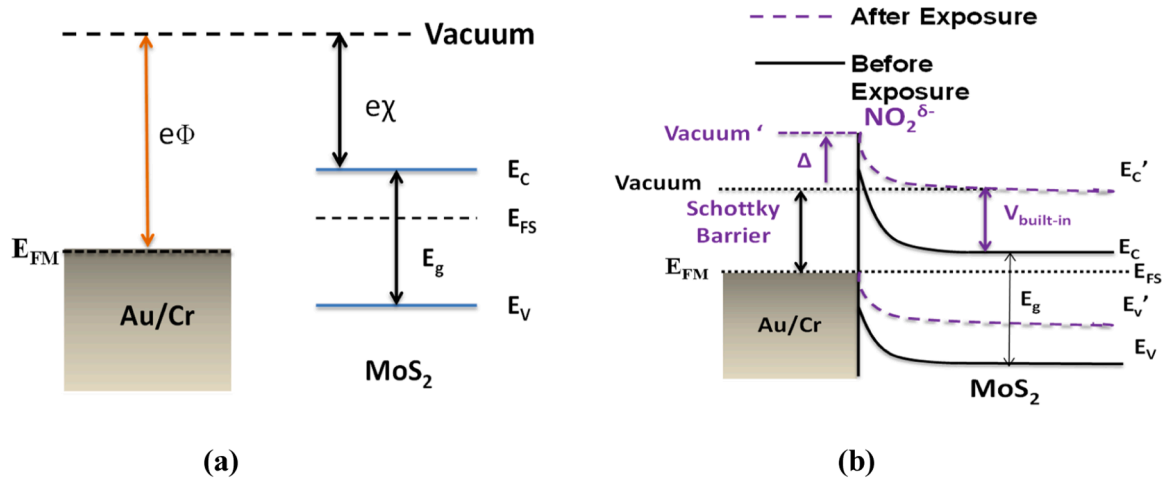
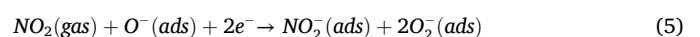
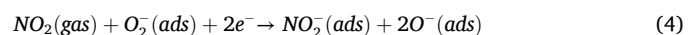


Fig. 7. (a) Schematic of energy band of Au/Cr metal system and single layer  $\text{MoS}_2$  in isolated state and under thermal equilibrium, and (b) band realignment and energy diagram of  $\text{MoS}_2$  and Au/Cr after Schottky barrier formation and dashed purple line show the change in energy band after  $\text{NO}_2$  exposure.

across the metal/2DSC interface through, (i) thermionic emission, (ii) thermionic field emission, and (iii) tunneling. The results are well established by Allain et.al. theoretically using DFT simulations as well as experimentally [45]. Based on this background, Au/Cr bilayer metal contact was used in the present work to provide a hybridized Schottky contact with  $\text{MoS}_2$ .

$\text{NO}_2$  being hazardous and toxic gas has been chosen as the target gas to study the conductance variation offered by single layer  $\text{MoS}_2$  and its behavior with channel modulation in back gate configuration. Fig. 5(a) shows the output curve of single layer  $\text{MoS}_2$  FET at  $V_{GS} = 1$  V obtained under before and after the 500 ppm exposure of  $\text{NO}_2$  gas with Zero Grade Air (ZGA) (80 %  $\text{N}_2 + 20$  %  $\text{O}_2$ ) as the carrier gas at room temperature ( $\sim 27^\circ\text{C}$ ). The value of gate voltage is chosen such that device is in the "ON" state and any slight change in channel conductance can be observed. There is significant decrease in conductance of FET when 500 ppm  $\text{NO}_2$  gas was exposed on the surface of single layer  $\text{MoS}_2$  (Fig. 5(a)) over the entire measure range of  $V_{DS}$ . The observed decrease in conductance is attributed to the oxidizing nature of  $\text{NO}_2$  gas. It was also observed that with further increase in gate voltage only the drain current value increases while change in conductance remains constant because device is already in ON state. Since  $\text{NO}_2$  is an oxidizing gas which accept

electrons from  $\text{MoS}_2$ , it reduces the number of charge carrier participating in the drain current, thereby reducing the  $I_{DS}$  (Fig. 5(a)) and hence lower the channel conductance. Apart from the  $\text{NO}_2$ , the  $\text{MoS}_2$  can also interact with the ambient oxygen to form  $\text{O}_2^-$  or  $\text{O}^-$  ions (Eqs. (1) and (2)). So, the  $\text{NO}_2$  molecules can either interact directly with  $\text{MoS}_2$  (Eq. (3)) or through these oxygen ions (Eqs. (4) and (5)) leading to a change in the resistance [48].



After the observance of significant decrease in conductance for 500 ppm  $\text{NO}_2$  exposure, a systematic variation in  $\text{NO}_2$  gas concentration (1 ppm to 500 ppm) was carried out as shown in Fig. 5(b). It may be noticed from Fig. 5(b) that there is systematic change in the conductance with

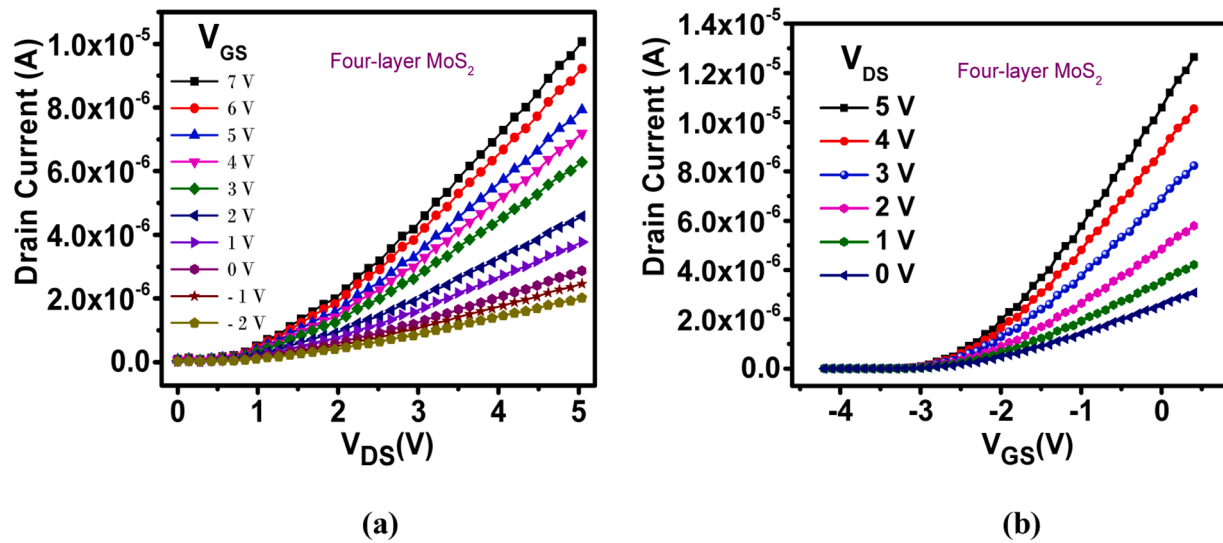


Fig. 8. (a) Output curves and (b) transfer curves of the fabricated four-layer MoS<sub>2</sub> channel-based FET devices.

increase in concentration of gas tested from 1 ppm to 500 ppm, showing high sensitivity of the fabricated sensor towards NO<sub>2</sub> gas. The sensitivity of the fabricated sensor can be estimated by quantifying the conductance change corresponding to each gas concentration. Sensor response (SR) can be defined as percentage change in the conductance value of the FET with and without gas exposure. If  $G_0$  is the channel conductance before the gas exposure and  $G_s$  is the conductance after the gas exposure, mathematically,

$$SR = \frac{G_0 - G_s}{G_s} \times 100\% \quad (6)$$

where,  $\Delta G = G_0 - G_s$  is the change in channel conductance with exposure to target gas. Fig. 4(c) shows the graph for SR with different concentration of NO<sub>2</sub> gas exposed to single layer MoS<sub>2</sub> FET on logarithmic scale. The SR (%) sensor was found to be 5.2, 52.8, 120, 242, 375 and 2280 towards 1, 5, 10, 50, 100 and 500 ppm concentration of NO<sub>2</sub> gas respectively. It can be noticed from Fig. 5(c) that there is linear variation of SR on log-log scale justifying the robust behavior of fabricated sensor.

To understand the mechanism of NO<sub>2</sub>-MoS<sub>2</sub> interaction and its aftermaths on the sensor response (SR), transfer curves were obtained for different concentration of gas. Fig. 6(a) shows the transfer curve of single layer MoS<sub>2</sub> FET without and with exposure to different concentration of NO<sub>2</sub> gas. Fig. 6(b) shows the change in threshold voltage with exposed gas concentration on logarithmic scale and inset shows the corresponding change on the linear scale. A monotonic increase in threshold voltage ( $V_{th}$ ) towards positive gate voltage is observed with increasing the concentration of NO<sub>2</sub> gas (Fig. 6(b)). This positive shift in the  $V_{th}$  suggests that understanding about the change in the channel conductance with NO<sub>2</sub> interaction is crucial to identify the sensing mechanism of MoS<sub>2</sub> FET sensor. The total resistance ( $R_{total}$ ) of the single layer MoS<sub>2</sub> FET is the sum of resistance offered by MoS<sub>2</sub> layer ( $R_{MoS_2}$ ) and contact resistance ( $R_{contact}$ ) that exists at metal contact (Au/Cr) and MoS<sub>2</sub> interface, i.e.

$$R_{total} = R_{MoS_2} + R_{contact} \quad (7)$$

It is well known that resistance of the semiconducting materials (MoS<sub>2</sub>) is inversely dependent on carrier concentration ( $N_c$ ), mathematically [49]

$$R_{semiconductor} \propto \frac{1}{N_c} \quad (8)$$

But contact resistance ( $R_{contact}$ ) is dependent on carrier concentration ( $N_c$ ) as well as the height of Schottky barrier ( $\phi$ ) that exists at the Au/Cr

and MoS<sub>2</sub> interface, i.e.

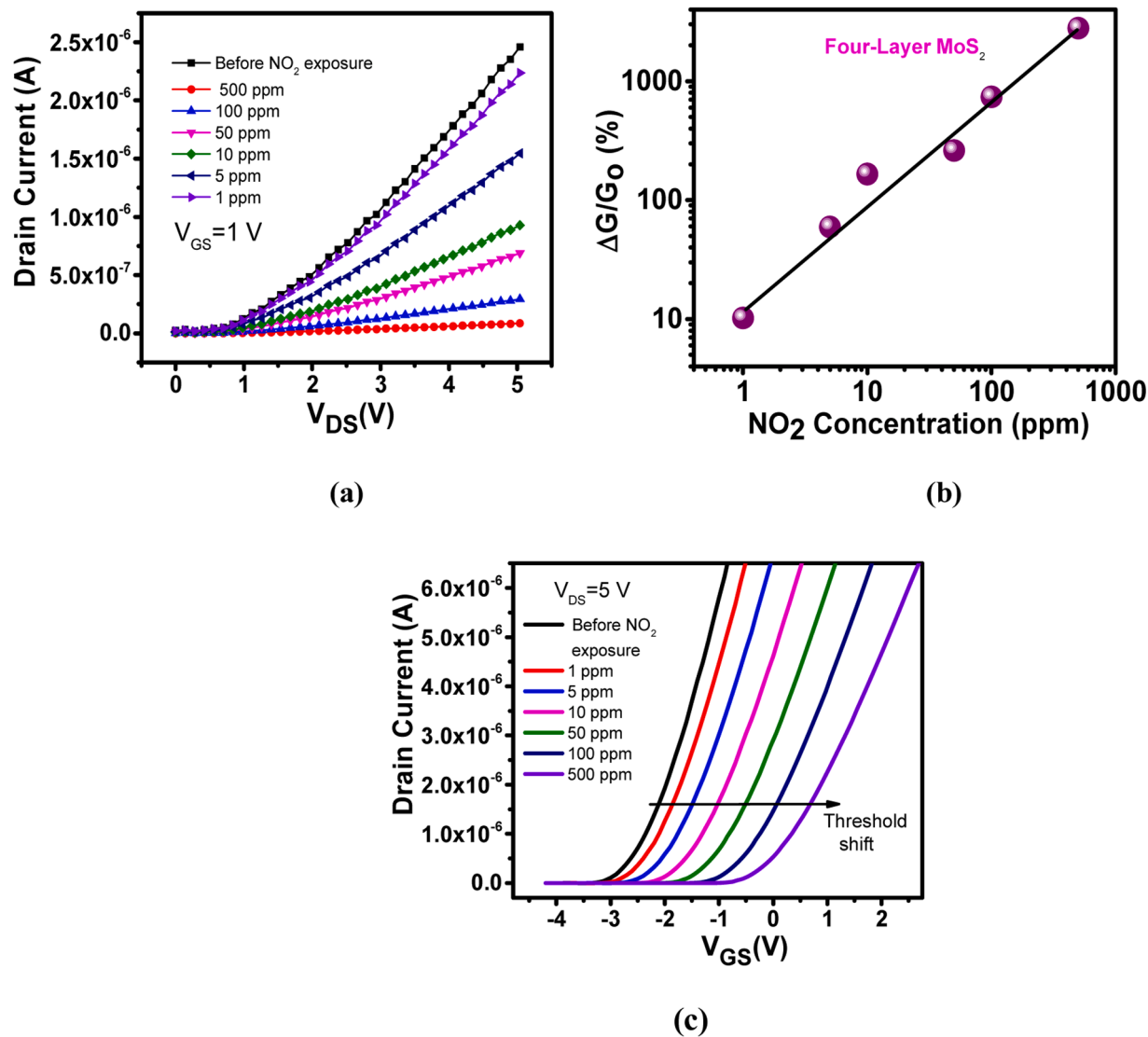
$$R_{contact} \propto \frac{1}{N_c} e^{(\phi/k_b T)} \quad (9)$$

Where  $k_b$  is Boltzmann's constant and  $T$  is the ambient temperature. Hence, any change in the electron concentration or Schottky barrier height will result in the change in conductance of the single layer MoS<sub>2</sub> FET. In the present case, there is charge transfer between NO<sub>2</sub> gas molecules and MoS<sub>2</sub> surface because NO<sub>2</sub> has one lone pair electron which tends to extract one electron from MoS<sub>2</sub> conduction band to make itself stable [50]. This way NO<sub>2</sub> acts as strong oxidizing agent and reduces the concentration of electron in conduction band of MoS<sub>2</sub>, thereby reducing the channel conductance with NO<sub>2</sub> interaction. Thus, after exposure to NO<sub>2</sub> gas, it requires more positive voltage at gate terminal to turn ON the fabricated transistor [33]. It is obvious that more concentration of NO<sub>2</sub> will reduce more electrons from conduction band of MoS<sub>2</sub> and thus more and more positive gate voltage is required for switching ON the transistor which can be clearly seen in Fig. 6(a) and (b). Further, the total conductance of the device is affected by the change in Schottky barrier height (Eqs. (7) and (9)).

Fig. 7(a) shows the schematic of energy band diagram corresponding to Au/Cr metal system and single layer MoS<sub>2</sub> in isolate state and under thermal equilibrium condition.  $E_{FS}$ ,  $E_c$ , and  $E_v$  in Fig. 7(a) represent the Fermi energy level, bottom of conduction band, top of valence band of single layer MoS<sub>2</sub> respectively, whereas, symbols  $E_{FM}$ ,  $\Phi$  represent the Fermi energy level and work function of metal (Cr) respectively, and  $\chi$  represents the electron affinity of single layer MoS<sub>2</sub> ( $\chi = 4.5$  eV). In the isolated state, fermi level of chromium ( $E_{FM}$ ) lies between the bottom of conduction band ( $E_c$ ) and top of valence band ( $E_v$ ) of single layer MoS<sub>2</sub> (Fig. 7(a)). Fig. 7(b) shows the schematic of energy band diagram when Au/Cr metal electrodes makes Schottky barrier with single layer MoS<sub>2</sub> under thermal equilibrium and modification in Schottky barrier (height and width) upon absorption of NO<sub>2</sub> gas. Since the deposited Au/Cr is making top contact with MoS<sub>2</sub> layer, work function of chromium ( $\Phi = 4.5$ ) is considered in Fig. 7(b). When chromium is in contact with MoS<sub>2</sub> layer, band bending of MoS<sub>2</sub> takes place to align the fermi levels and there exist a Schottky barrier with height:

$$\phi(eV) = \Phi(\text{chromium}) - \chi(\text{single layer MoS}_2) \quad (10)$$

As discussed earlier, on exposure of the sensor device with NO<sub>2</sub> gas, conductance change of the device is dependent on majorly two phenomena, (i) transfer of charge from MoS<sub>2</sub> to NO<sub>2</sub> gas, and (ii) change in Schottky barrier upon gas exposure. The width of the Schottky barrier



**Fig. 9.** (a) Output curve for four-layer MoS<sub>2</sub> FET sensor without NO<sub>2</sub> exposure and exposure to different concentration of NO<sub>2</sub> from 1 ppm to 500 ppm, (b) four-layer MoS<sub>2</sub> FET sensor response variation with concentration of NO<sub>2</sub> gas on logarithmic scale, and (c) transfer curve at V<sub>DS</sub> = 5 V of fabricated four-layer MoS<sub>2</sub> FET sensor towards NO<sub>2</sub> gas from 1 ppm to 500 ppm gas concentration.

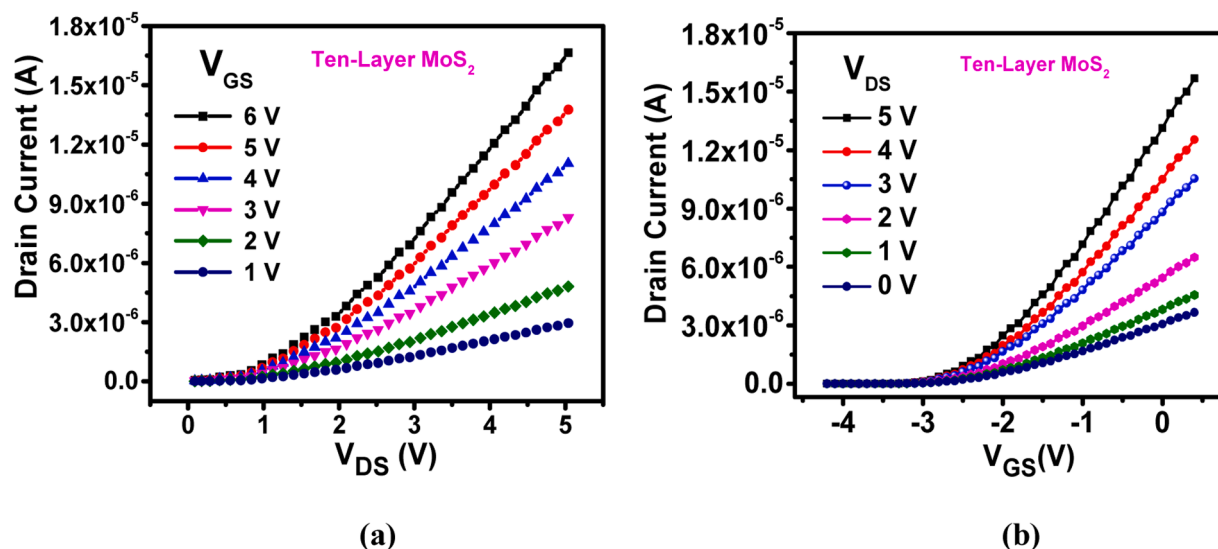


Fig. 10. (a) Output curves, and (b) transfer curve of the fabricated ten-layer MoS<sub>2</sub> channel-based FET device.

will increase and built-in potential ( $V_{\text{built-in}}$ ) will modify when absorption of NO<sub>2</sub> gas takes place (Fig. 7(b)). With reduction in electron concentration in conduction band of MoS<sub>2</sub> upon absorption of NO<sub>2</sub> gas, fermi level of MoS<sub>2</sub> will move downwards. This downward movement of fermi level will result in increment in Schottky barrier width and reduces  $V_{\text{built-in}}$ , resulting in overall decrement in current in the device (Fig. 7(b)) [51–53]. NO<sub>2</sub> withdraw electrons from the MoS<sub>2</sub> and become NO<sub>2</sub><sup>−</sup> (negatively charged species) which increases the height of Schottky barrier ( $\Delta$ ) as shown in Fig. 7(b). This kind of increase is commonly found in literature, e.g. oxygen in oxidative state increases the Schottky barrier height of ZnO nanowires and created profound effect in performance of ZnO nanowire transistor [54]. Hence, upon exposure of NO<sub>2</sub> gas, conductance of the single layer MoS<sub>2</sub> FET decreases due to both modification in Schottky barrier and transfer of charge phenomenon.

### 3.3. Gas sensing using four-layer and ten-layer MoS<sub>2</sub> as sensing matrix

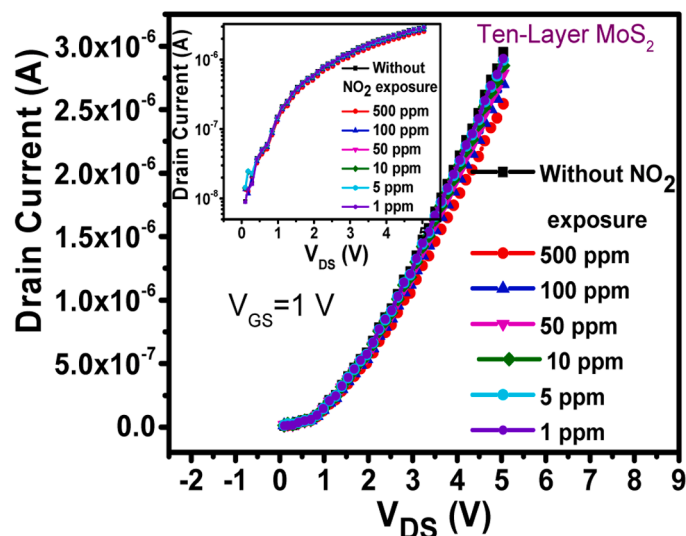
Gas sensing is a surface-controlled process. It is to understand that only certain thickness i.e. 80 nm to 100 nm of sensing matrix (especially in oxide) semiconductors such as Tin oxide (SnO<sub>2</sub>), Zinc oxide (ZnO) etc. participates in the interaction with analytes [55]. When adsorption of gas takes place, fix depth of electron depletion layer of thickness range 2–100 nm is formed [21]. This depth is called Debye length ( $L$ ) which is defined as the distance over which maximum charge separation can take place. When crystallite size ( $D$ ) is smaller than  $2L$ , each grain is depleted of conducting electrons and the resistance offered by the grains control the sensing response and mechanism is called grain control [21]. To identify the optimum thickness of MoS<sub>2</sub>, four-layer and ten-layer MoS<sub>2</sub> as gas sensing matrix was also investigated in the present work. Fig. 8(a) and (b) show the output and transfer curves for the MoS<sub>2</sub> FET fabricated using four-layer MoS<sub>2</sub> as channel layer. Fig. 8(a) again shows the expected Schottky contact formation of Cr with MoS<sub>2</sub> layers. It can be noticed from Fig. 8(b) that drain current values has increased from  $1.45 \times 10^{-6}$  A (case of single layer MoS<sub>2</sub> sensor) to  $1.28 \times 10^{-5}$  A at  $V_{\text{DS}} = 5$  V and  $V_{\text{GS}} = 1$  V for four-layer MoS<sub>2</sub> device. This increase in the drain current is likely due to increased density of states (number of electrons) for the case of four-layer MoS<sub>2</sub> compared to single-layer MoS<sub>2</sub>

[56]. The fabricated transistor shows expected n-type behavior of semiconducting MoS<sub>2</sub> with a threshold voltage of  $-2.62$  V (Fig. 8(b)). The mobility of the device using four-layer MoS<sub>2</sub> was estimated to be  $26.8 \text{ cm}^2\text{V}^{-1}\text{s}^{-1}$  with current on/off ratio of  $4.2 \times 10^5$ . The mobility and current on/off ratio both increases for the case of four-layer MoS<sub>2</sub> FET compared to the corresponding value obtained for single layer MoS<sub>2</sub> based FET.

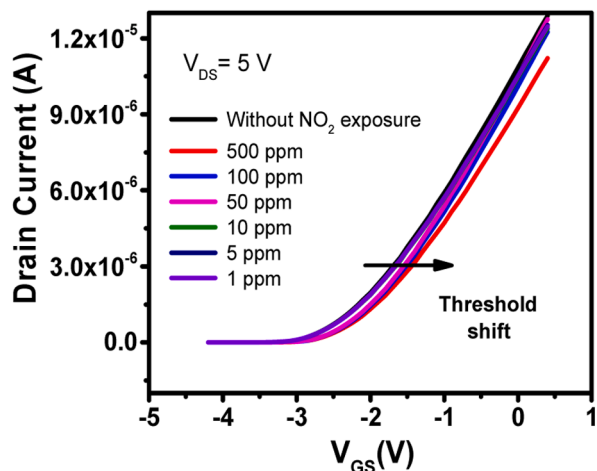
To check the gas sensing behavior of four-layer MoS<sub>2</sub> FET, different concentrations of 1, 5, 10, 50, 100 and 500 ppm of NO<sub>2</sub> gas was exposed separately in gas testing chamber. Fig. 9(a) shows the output curves of FET sensor obtained at  $V_{\text{GS}} = 1$  V when sensor was exposed to different gas concentrations. As expected, drain current is seen to be continuously decreasing with increasing the NO<sub>2</sub> gas concentration at a fixed value of  $V_{\text{GS}}$  and all measured values of  $V_{\text{DS}}$ . Variation of Sensor Response (SR) with NO<sub>2</sub> gas concentration on logarithmic scale is shown in Fig. 9(b). The SR (%) sensor was found to be 10.2, 59.4, 165.3, 261.1, 737 and 2790 towards 1, 5, 10, 50, 100 and 500 ppm concentration of NO<sub>2</sub> gas respectively. It can be noticed from Fig. 9(b) that there is linear variation of SR on log-log scale as observed for the case of single layer, justifying the robust behavior. Fig. 9(c) shows the transfer curve obtained for the four-layer MoS<sub>2</sub> FET without and with exposure to different concentration of NO<sub>2</sub> gas. A monotonic increase in threshold voltage ( $V_{\text{th}}$ ) towards positive gate voltage is observed with increasing the concentration of NO<sub>2</sub> gas (Fig. 9(c)). This increment is consistent with results obtained for single layer MoS<sub>2</sub> FET based sensor (Fig. 6(a)).

Fig. 10(a) and (b) show the output curves and transfer curves obtained for ten-layer MoS<sub>2</sub> FET device respectively.

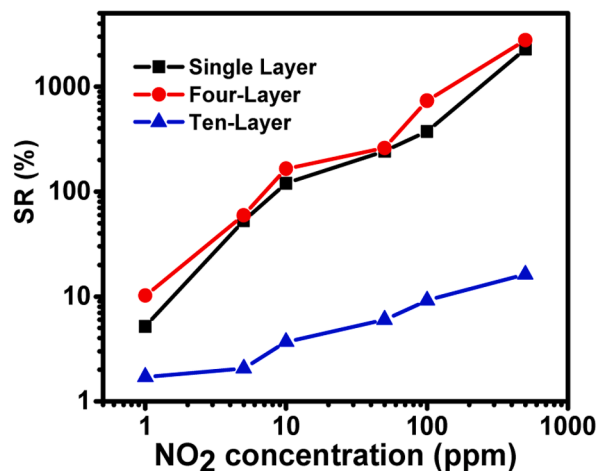
To observe the gas sensing response, different concentration of NO<sub>2</sub> gas from 500 to 1 ppm was introduced systematically into the test chamber separately and its effect on the transfer and output curves were recorded as shown in Fig. 11(a) and (b) where inset of Fig. 10(a) shows the variation on semi-log scale. A slight change in the drain current was observed with a SR of 16.2 % towards 500 ppm NO<sub>2</sub> gas (Fig. 11(a)). However, SR was reduced for the lower concentrations (SR of 9.1 % for 100 ppm, SR of 6 % for 50 ppm, SR of 3.7 % for 10 ppm, SR of 2.06 % for 5 ppm and SR of 1.71 % for 1 ppm) which is lower than the corresponding values obtained for devices using single layer (Fig. 5(c)) and



(a)



(b)



(c)

Fig. 11. (a) Output curve for ten-layer MoS<sub>2</sub> sensor (inset shows the variation on semi-log scale), (b) transfer curves obtained for ten-layer MoS<sub>2</sub> FET sensor without NO<sub>2</sub> exposure and exposure to different concentration of NO<sub>2</sub> from 1 ppm to 500 ppm, and (c) comparison of sensing response between single layer, four-layer and ten-layer MoS<sub>2</sub> FET sensors with concentration of NO<sub>2</sub> gas.

Table 3

Values of conductance in absence and presence of 10 ppm NO<sub>2</sub> gas and sensing response for single layer, four layer and ten-layer MoS<sub>2</sub> based FET structures.

No. of MoS <sub>2</sub> layers	G <sub>0</sub> (Siemens)	G <sub>s</sub> (Siemens)	SR (%)
Single	$4.39 \times 10^{-8}$	$2.0 \times 10^{-8}$	120
Four	$3.76 \times 10^{-7}$	$1.42 \times 10^{-7}$	165.3
Ten	$4.51 \times 10^{-7}$	$4.35 \times 10^{-7}$	3.69

four-layer MoS<sub>2</sub> (Fig. 9(b)) channel. The obtained results signify the lesser sensitivity of the fabricated device with ten-layer MoS<sub>2</sub> as sensing matrix. Transfer curve of ten-layer MoS<sub>2</sub> was also traced for the exposure of 500 ppm to 1 ppm NO<sub>2</sub> gas concentration (Fig. 11(b)). There was slight change in the threshold voltage on exposure of 500 ppm gas, however a negligible change was observed for lower concentrations (100 ppm to 1 ppm) as expected from the SR observed in the output characteristics. Fig. 11(c) shows the graph of SR (%) with concentrations of NO<sub>2</sub> gas for FET sensors having single layer, four-layer and ten-layer MoS<sub>2</sub> channels for comparison. It can be noticed from Fig. 11(c) that SR

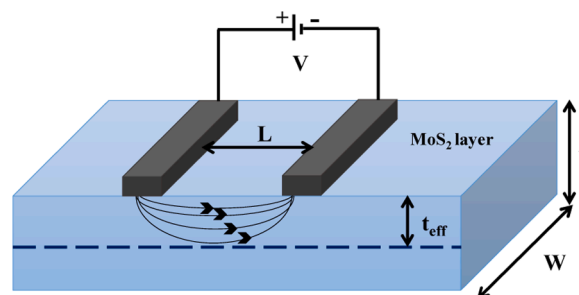
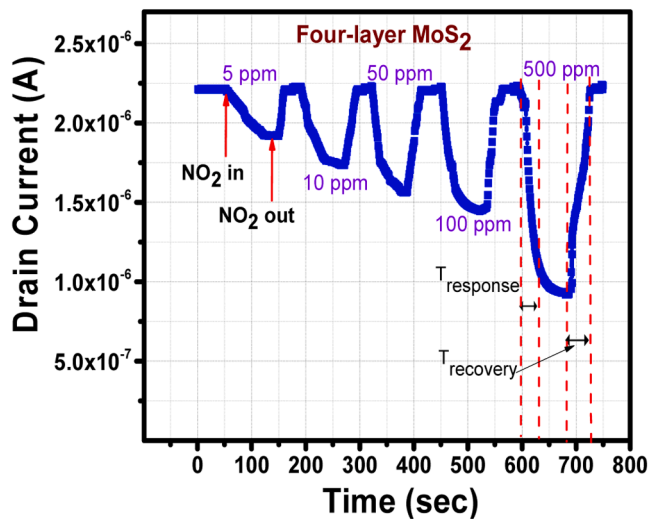
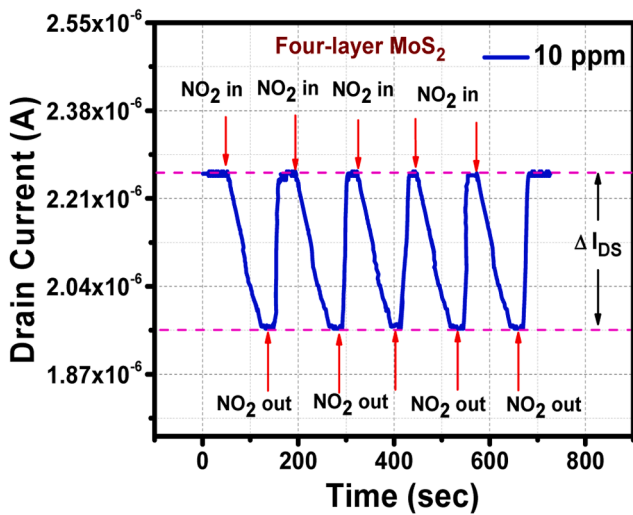


Fig. 12. Schematic of sensing structure showing electric field profile for effective thickness upto which maximum interaction is possible.

(%) is maximum for the FET sensor having four-layer MoS<sub>2</sub> compared to single layer and ten-layer MoS<sub>2</sub> sensors for each NO<sub>2</sub> concentration. It is concluded that MoS<sub>2</sub> sensor with four-layer MoS<sub>2</sub> as sensing matrix is optimum for the high performance NO<sub>2</sub> gas sensor.



(a)



(b)

Fig. 13. Transient response of 4 layers MoS<sub>2</sub> FET sensor (a) towards different concentration of NO<sub>2</sub> gas, and (b) towards 10 ppm of NO<sub>2</sub> gas with 5 repeated cycles.

### 3.4. Explanation of higher sensitivity achieved for four-layer MoS<sub>2</sub> FET sensor

The higher sensing response of four-layer MoS<sub>2</sub> based FET structure as compared to single layer and ten-layer MoS<sub>2</sub> structure can be well understood in terms of conductance change with number of MoS<sub>2</sub> layers upon interaction with NO<sub>2</sub> gas. Table 3 summarizes the value of conductance in presence ( $G_S$ ) and absence ( $G_0$ ) of 10 ppm of NO<sub>2</sub> gas. The value of conductance is found to be,  $G_0 = 4.39 \times 10^{-8}$  S and  $G_S = 2.0 \times 10^{-8}$  S for single layer,  $G_0 = 3.76 \times 10^{-7}$  S and  $G_S = 1.42 \times 10^{-7}$  four-layer and  $G_0 = 4.51 \times 10^{-7}$  S and  $G_S = 4.35 \times 10^{-7}$  for ten-layer MoS<sub>2</sub> FET structure respectively towards 10 ppm of NO<sub>2</sub> gas. The conductance ( $G = 1/R$ ) of a FET structure having MoS<sub>2</sub> sensing layer can be expressed as a function of film thickness as

$$G = \frac{1}{R_a} = \frac{A\sigma}{L} = \frac{Wt\sigma}{L} \quad (11)$$

where,  $\sigma$  is electrical conductivity and  $t$  is the thickness of MoS<sub>2</sub> layer,

and  $L$  and  $W$  are the distance between two electrodes and length of electrodes respectively as shown in Fig. 11. The Eq. (11) is valid for the FET structure having MoS<sub>2</sub> layer of thickness over the range  $t = 0$  to  $t_{eff}$ , where  $t_{eff}$  is the effective thickness of sensing layer upto which applied electric field is confined (Fig. 12) i.e. about four layer. If  $t > t_{eff}$ ,  $G = \left(\frac{W\sigma}{L}\right)t_{eff}$ , and  $G$  of prepared sensor must show a lesser sensitivity beyond a certain thickness if there is lesser availability of electrons to interact with incoming analyte. Since, gas sensing is a surface dominating phenomenon, it limits the number of gas molecules to get chemically adsorbed on the surface of the sensing matrix. NO<sub>2</sub> gas molecules can easily get diffused on the surface of MoS<sub>2</sub> upto a certain thickness (space-charge layer). This diffusion on MoS<sub>2</sub> surface for the case of four-layer MoS<sub>2</sub>, increases the probability of charge transfer process since electron from all the four-layer MoS<sub>2</sub> channel can participate and hence maximum probability of decrement in the conductance is expected resulting in great improvement in SR [50]. While, for the case of single layer MoS<sub>2</sub>, NO<sub>2</sub> gas molecules does not have any access to go deep so lesser amount of diffusion can take place resulting in lesser quantity of adsorption which in turn leads to comparably lesser probability of charge transfer between MoS<sub>2</sub> and NO<sub>2</sub>. This lesser charge transfer means lesser change in conductance hence lower sensitivity for the case of single layer MoS<sub>2</sub>. There is a very small change in the conductance value on exposure to gas in ten-layer MoS<sub>2</sub> FET structure leading to poor sensing performance. This may be attributed to the fact that on further increasing the number of layers (more than four layers), there is saturation in effective thickness ( $t_{eff}$ ) of the sensing matrix as well as the increased interlayer resistance (due to increment in vdW gap) limits the number of electron (due to loss of gate electrostatic control with increased thickness) to participate in the interaction with incoming NO<sub>2</sub> gas, resulting in the poor sensing response of bulk MoS<sub>2</sub>. However, for the case of four-layer MoS<sub>2</sub> sensor, there is effective gate electrostatic control such that electron from all the four layers can participate in the space charge formation resulting in very high probability of electron transfer, thus higher sensing response. Thus, four-layer MoS<sub>2</sub> is identified as the effective thickness give maximum change in the value of conductance and hence higher sensing response.

### 3.5. Response time of four-layer MoS<sub>2</sub> FET sensor

Fig. 13(a) shows the transient response (variation in drain current with time) of the prepared four-layer MoS<sub>2</sub> based device as a function of time for different concentrations of NO<sub>2</sub> gas ranging from 5 ppm to 500 ppm. The drain current values are found to be decreasing from  $2.26 \times 10^{-6}$  A (without NO<sub>2</sub> exposure) to  $1.89 \times 10^{-6}$  A (5 ppm NO<sub>2</sub> gas),  $1.74 \times 10^{-6}$  A (10 ppm NO<sub>2</sub>),  $1.56 \times 10^{-6}$  A (50 ppm NO<sub>2</sub>),  $1.44 \times 10^{-6}$  A (100 ppm) and  $9.2 \times 10^{-7}$  A (500 ppm NO<sub>2</sub>) gas (Fig. 12(a)). The response time of the FET sensor can be defined as time required for the 90 % change in the conductance value at a particular gas concentration. The response ( $T_{response}$ ) and recovery time ( $T_{recovery}$ ) of fabricated four-layer MoS<sub>2</sub> channel based device is found to be 24 s and 41 s respectively (Fig. 13(a)). This response time at room temperature is comparable to the recent reported values for conducting polymers and carbon nanotubes and also to MoS<sub>2</sub> based gas sensors [40,57,58,59]. Fig. 13(b) shows the transient response of fabricated four-layer MoS<sub>2</sub> device towards 10 ppm NO<sub>2</sub> gas with 5 repeated cycle to identify the repeatability and reproducibility. The fabricated sensor exhibits similar response characteristics for each cycle without showing any drift in the drain current values (Fig. 13(b)). The obtained result suggests that fabricated four-layer device is highly stable and repeatable towards NO<sub>2</sub> gas.

### 3.6. Cross-selectivity studies of four-layer MoS<sub>2</sub> FET sensor

The fabricated four-layer MoS<sub>2</sub> FET sensor was tested for cross-selectivity with different interfering gases. Fig. 14(a) shows the response ( $I_{DS}$ - $V_{DS}$ ) curve of four-layer MoS<sub>2</sub> based FET sensor recorded

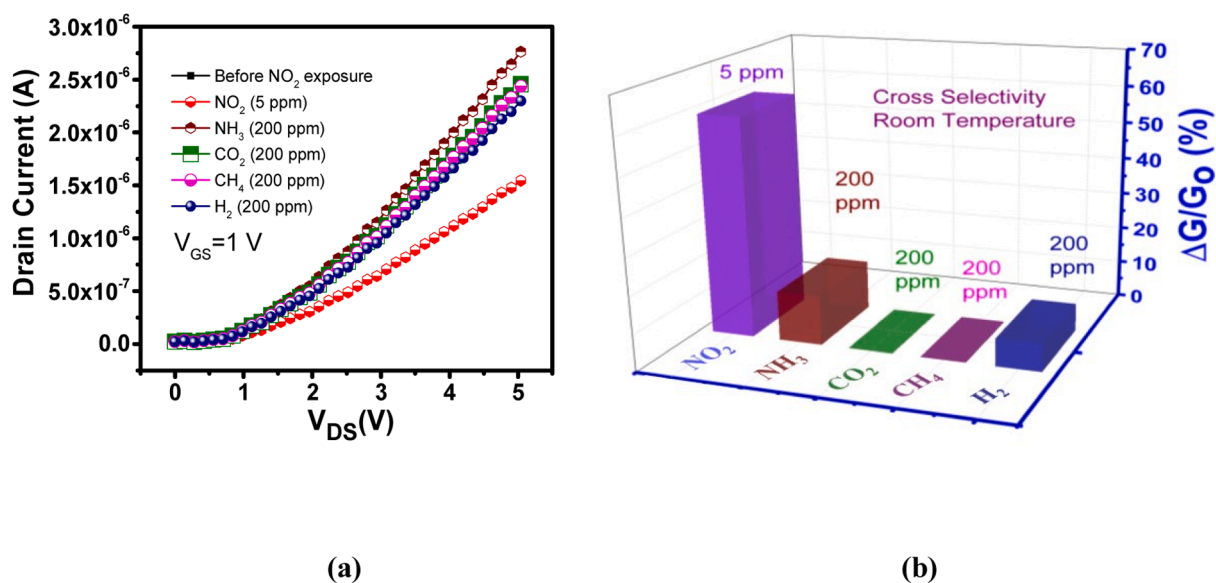


Fig. 14. (a) Output characteristics curves of fabricated four-layer MoS<sub>2</sub> FET obtained for NH<sub>3</sub>, CO<sub>2</sub>, CH<sub>4</sub> and H<sub>2</sub> gases at 200 ppm, NO<sub>2</sub> at 5 ppm, and (b) histogram for obtained sensor response for different interfering gases.

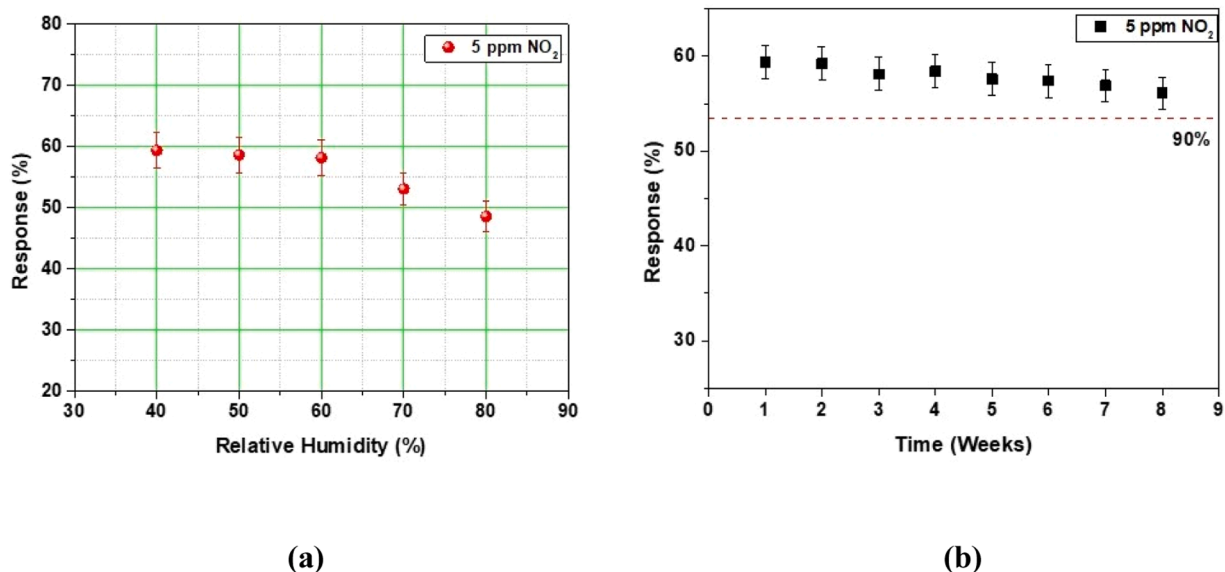


Fig. 15. (a) Effect of humidity on the sensor response and (b) stability of the sensor response towards 5 ppm NO<sub>2</sub>.

Table 4

Gas sensing response of different gases for four-layer MoS<sub>2</sub> sensor structure operating at room temperature.

Different gases	Gas concentration (ppm)	Sensor response (%)
NO <sub>2</sub>	5	59.4
NH <sub>3</sub>	200	13.4
CO <sub>2</sub>	200	0.1
CH <sub>4</sub>	200	0.16
H <sub>2</sub>	200	7.5

at  $V_{GS} = 1$  V for ammonia (NH<sub>3</sub>), CO<sub>2</sub> (carbon dioxide), methane (CH<sub>4</sub>) and hydrogen (H<sub>2</sub>) at very high concentration of 200 ppm, whereas corresponding response for target gas (NO<sub>2</sub>) of 5 ppm only. All gases were obtained from highly pure (> 99 %) cylinders of gases procured commercially. It is to be noticed that NH<sub>3</sub> being electron donor increases the electron density in the MoS<sub>2</sub> channel and hence increase in the drain current can be noticed towards 200 ppm NH<sub>3</sub> gas. No significant change

in the drain current was observed towards other interfering gases. Fig. 14(b) shows the histogram for sensor response obtained for interfering gases where sensor response was calculated using Eq. (6). It can be observed from Fig. 14(b) that fabricated sensor shows the maximum response of 37.2 % even at low concentration of 5 ppm NO<sub>2</sub> gas as compared to sensing response towards other gases of higher concentration of 200 ppm. The effect of humidity and the stability of the sensor were also studied and are displayed in Fig. 15. It is evident from Fig. 15 (a) that up to a relative humidity of 60 %, there is a minor variation in the sensor response towards 5 ppm NO<sub>2</sub>, while a higher value of relative humidity (> 60 %) interferes with the sensing behaviour. The stability of the sensor response towards 5 ppm NO<sub>2</sub> was evaluated over a period of 8 weeks and it was found the sensor exhibit a change in response of < 10 % over the 8 weeks as shown in Fig. 15(b).

Table 4 summarizes the sensor response obtained for four-layer MoS<sub>2</sub> sensing structure for various interfering gases at higher concentrations. The obtained result show the possible application of fabricated sensor towards room temperature operated NO<sub>2</sub> gas sensor without

**Table 5**

Comparison of the sensor with other room temperature 2D materials-based FET sensors for NO<sub>2</sub>.

Material	NO <sub>2</sub> concentration (ppm)	Response (%)	Ref
MoTe <sub>2</sub>	0.001	140	[60]
Graphene	1	6	[61]
NbSe <sub>2</sub> /WSe <sub>2</sub>	5	34	[62]
WSe <sub>2</sub>	5	0.4	[63]
MoS <sub>2</sub>	200	8	[64]
Black Phosphorus	0.02	20	[65]
MoS <sub>2</sub>	5	59.4	Present work

interference with other gases. The fabricated gas sensor was also compared with other 2D materials-based FET sensors operating at room temperature. Although, the MoTe<sub>2</sub> based sensor fabricated by Feng et al. shows a higher response, it requires high gate biasing (60 V) in order to obtain proper recovery [60]. The comparison is summarised in Table 5.

#### 4. Conclusions

PLD grown MoS<sub>2</sub> layers were exploited for gas sensing applications using MoS<sub>2</sub> as gas sensing matrix based back gated FETs. Three different thickness of MoS<sub>2</sub>, (i) single layer, four-layer, and (ii) ten-layer MoS<sub>2</sub> were chosen to see the significant effect of change in surface to volume ratio on gas sensing performance of the MoS<sub>2</sub> FETs. Schottky contact on MoS<sub>2</sub> layers using Au/Cr is used as source-drain electrodes and output curves and transfer curves were obtained. Systematic gas sensing experiments were carried out from 1 ppm to 500 ppm on fabricated sensor structures i.e. Au/Cr/single layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si, Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si and Au/Cr/ten-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si, using output and transfer curves. Effect of NO<sub>2</sub> gas adsorption on MoS<sub>2</sub> was expalined using realignment of energy band diagram. Sensing response (%) for Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si structure was found to be maximum as comapred to the case of single layer and ten-layer. To see the selectivity of optimized Au/Cr/four-layer MoS<sub>2</sub>/Si<sub>3</sub>N<sub>4</sub>/Si sensor structure, sensor was exposed to different interferring gases including NH<sub>3</sub>, CH<sub>4</sub>, CO<sub>2</sub> and H<sub>2</sub> and it was found that optimized sensor is highly selective towards NO<sub>2</sub> gas.

#### Availability of data and materials

Not Applicable.

#### Funding

Not Applicable

#### CRedit authorship contribution statement

**Sujit Kumar:** Writing – original draft, Methodology, Investigation, Formal analysis, Data curation, Conceptualization. **Anjali Sharma:** Writing – review & editing, Validation, Supervision, Formal analysis. **Ajay K. Sao:** Investigation. **Jatinder Pal Singh:** Writing – review & editing, Investigation. **Arijit Chowdhuri:** Supervision, Validation. **Monika Tomar:** Writing – review & editing, Validation, Supervision, Resources.

#### Declaration of competing interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

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